

<b>Issue Classification</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10015322	DANSIE ET AL.
	Examiner	Art Unit
	Nano, Sargon N	2157

Nano, Sargon N (Assistant Examiner)	7/20/2007 (Date)	 ARIC ETIENNE <del>SUPERVISORY PATENT EXAMINER</del>	Total Claims Allowed: 10
(Legal Instruments Examiner)	(Date)	(Primary Examiner)	(Date)